

A Minkowski Sum Interval Analysis Approach for Planar Arrays Sensitivity Analysis

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Abstract

In this work, the analysis the excitation tolerances on the radiation performances of planar phased arrays is dealt with. An innovative sensitivity tool is proposed, based on interval arithmetic and the Minkowski sum. Narrow but inclusive bounds can be analytically derived on the radiation pattern starting from the tolerances on the array excitations (both in amplitude and in phase). Moreover, thanks to the Minkowski sum, narrower intervals are estimated with respect to standard interval analysis (*IA*) tools based on the Cartesian rules. Some numerical results are shown, in order to verify the effectiveness of the developed approach, by analyzing planar arrays of different sizes.

1 Numerical Assessment - Analysis vs Number of Radiating Element $N \times M$

GOAL: This section considers the study of the influence of tolerances on the control points (in amplitude and phase) in planar array with different size. Accordingly, the test case considers different planar geometries, i.e, 8×6 , 12×8 , 16×8 and 20×10 elements for which the element excitations have been choosen to generate on the principals planes $u = 0$ and $v = 0$ a Dolph-Chebyshev pattern with SLL equal to -20 dB. The amplitude and phase tolerances have been choosen as: $\pm 0\%$, $\pm 10\%$ for the amplitude and ± 1 , ± 5 and ± 10 [deg] for the phase.

Array geometry:

- Uniform planar array: $N \times M = 8 \times 6$, $N \times M = 12 \times 8$, $N \times M = 16 \times 8$, $N \times M = 20 \times 10$.
- Inter-element spacing: $d_x = 0.5 [\lambda]$ - $d_y = 0.5 [\lambda]$;

Nominal control points:

- Separable distributions:
 - x -axis: Dolph-Chebyshev pattern: $SLL = 20$ [dB].
 - y -axis: Dolph-Chebyshev pattern: $SLL = 20$ [dB].

Tolerances on the control points:

- Amplitude tolerance: $\delta\alpha_n = \pm 0\%$, $\pm 10\%$.
- Phase tolerance: $\delta\beta_n = \pm 1$ [deg], ± 5 [deg], ± 10 [deg].

Minkowski sum parameters:

- Number of sides including polygon: $L = 720$

1.1 Analysis vs NxM

1.1.1 Pattern Features - Interval Beamwidth

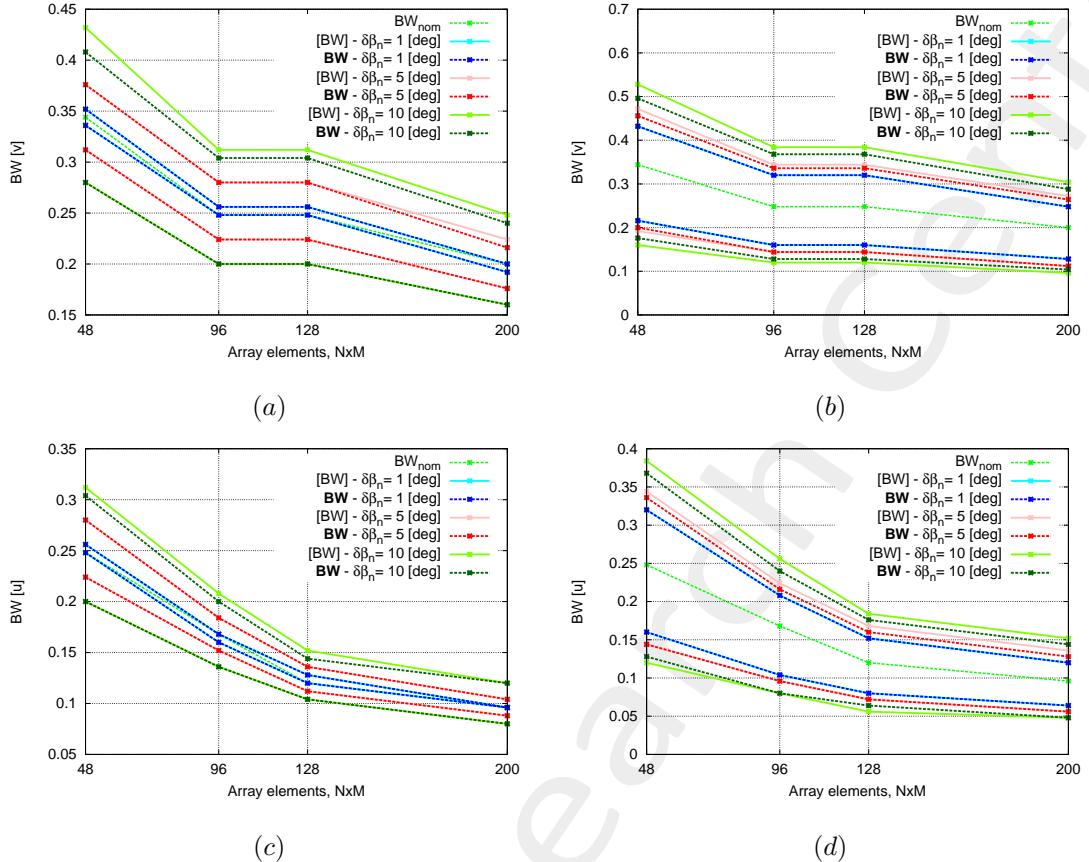


Table: Interval Beamwidth comparison Cartesian vs Minkowski sum

(a) $\delta\alpha_n = 0\%$ - plane $u = 0$, (b) $\delta\alpha_n = 10\%$ - plane $u = 0$

(c) $\delta\alpha_n = 0\%$ - plane $v = 0$, (d) $\delta\alpha_n = 10\%$ - plane $v = 0$

Amplitude Error: $\delta\alpha_n = 0\%$ - Plane $u = 0$

$N \times M / \delta\beta_n$ [deg]	Cartesian			Minkowski		
	1	5	10	1	5	10
48	[0.336, 0.352]	[0.312, 0.376]	[0.280, 0.432]	[0.336, 0.352]	[0.312, 0.376]	[0.280, 0.408]
96	[0.248, 0.256]	[0.224, 0.280]	[0.200, 0.312]	[0.248, 0.256]	[0.224, 0.280]	[0.200, 0.304]
128	[0.248, 0.256]	[0.224, 0.280]	[0.200, 0.312]	[0.248, 0.256]	[0.224, 0.280]	[0.200, 0.304]
200	[0.192, 0.200]	[0.176, 0.224]	[0.160, 0.248]	[0.192, 0.200]	[0.176, 0.216]	[0.160, 0.240]

Table: Interval Beamwidth vs $N \times M$ - $\delta\alpha_n = 0\%$ - Cartesian vs Minkowski sum

Amplitude Error: $\delta\alpha_n = 0\%$ - **Plane** $v = 0$

$N \times M / \delta\beta_n$ [deg]	Cartesian			Minkowski		
	1	5	10	1	5	10
48	[0.248, 0.256]	[0.224, 0.280]	[0.200, 0.312]	[0.248, 0.256]	[0.224, 0.280]	[0.200, 0.312]
96	[0.160, 0.168]	[0.152, 0.184]	[0.136, 0.208]	[0.160, 0.168]	[0.152, 0.184]	[0.136, 0.208]
128	[0.120, 0.128]	[0.112, 0.136]	[0.104, 0.152]	[0.120, 0.128]	[0.112, 0.136]	[0.104, 0.152]
200	[0.096, 0.096]	[0.088, 0.104]	[0.080, 0.120]	[0.096, 0.096]	[0.088, 0.104]	[0.080, 0.120]

Table: Interval Beamwidth vs $N \times M - \delta\alpha_n = 0\%$ - Cartesian vs Minkowski sum

Amplitude Error: $\delta\alpha_n = 10\%$ - **Plane** $u = 0$

$N \times M / \delta\beta_n$ [deg]	Cartesian			Minkowski		
	1	5	10	1	5	10
48	[0.216, 0.432]	[0.192, 0.472]	[0.160, 0.528]	[0.216, 0.432]	[0.200, 0.456]	[0.176, 0.496]
96	[0.160, 0.320]	[0.144, 0.344]	[0.120, 0.384]	[0.160, 0.320]	[0.144, 0.336]	[0.128, 0.368]
128	[0.160, 0.320]	[0.144, 0.344]	[0.120, 0.384]	[0.160, 0.320]	[0.144, 0.336]	[0.128, 0.368]
200	[0.128, 0.248]	[0.112, 0.272]	[0.096, 0.304]	[0.128, 0.248]	[0.112, 0.264]	[0.104, 0.288]

Table: Interval Beamwidth vs $N \times M - \delta\alpha_n = 10\%$ - Cartesian vs Minkowski sum

Amplitude Error: $\delta\alpha_n = 10\%$ - **Plane** $v = 0$

$N \times M / \delta\beta_n$ [deg]	Cartesian			Minkowski		
	1	5	10	1	5	10
48	[0.160, 0.320]	[0.144, 0.344]	[0.120, 0.384]	[0.160, 0.320]	[0.144, 0.336]	[0.128, 0.368]
96	[0.104, 0.208]	[0.096, 0.224]	[0.080, 0.256]	[0.104, 0.208]	[0.096, 0.216]	[0.080, 0.240]
128	[0.080, 0.152]	[0.072, 0.168]	[0.056, 0.184]	[0.080, 0.152]	[0.072, 0.160]	[0.064, 0.176]
200	[0.064, 0.120]	[0.056, 0.136]	[0.048, 0.152]	[0.064, 0.120]	[0.056, 0.128]	[0.048, 0.144]

Table: Interval Beamwidth vs $N \times M - \delta\alpha_n = 0\%$ - Cartesian vs Minkowski

1.1.2 Pattern Features - Interval SLL

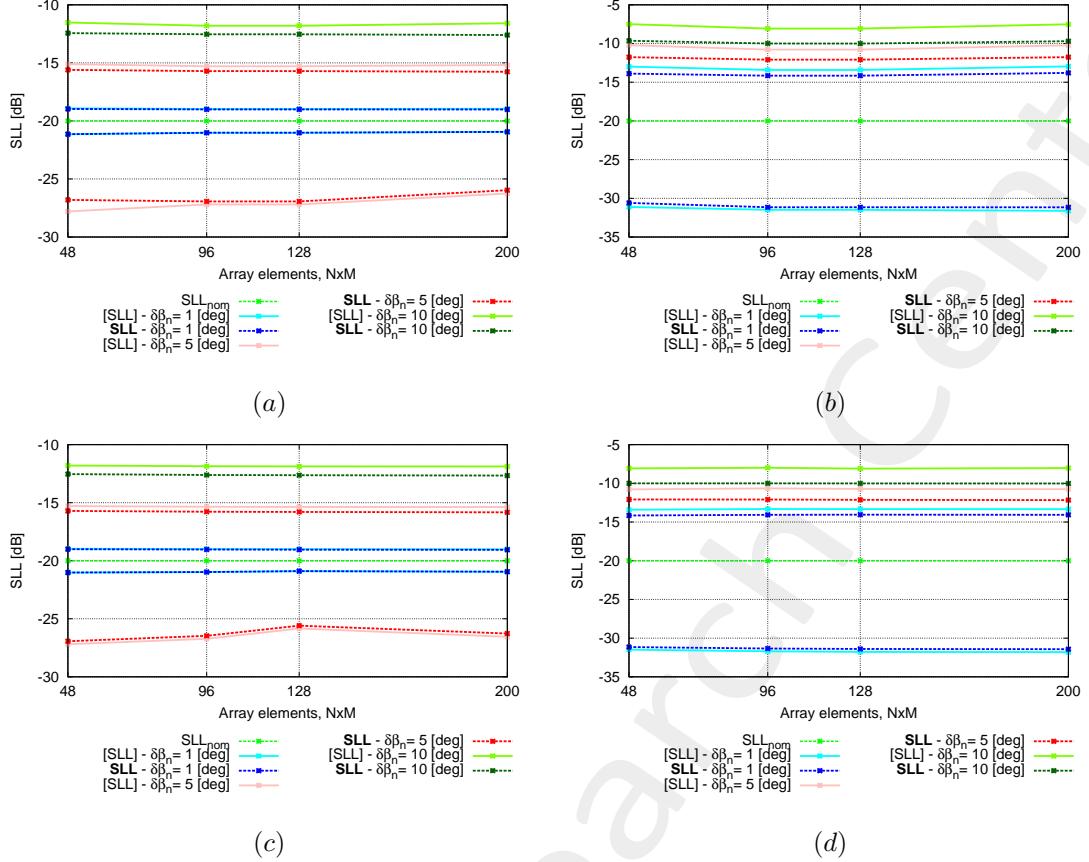


Table: Interval *SLL* comparison Cartesian vs Minkowski sum

(a) $\delta\alpha_n = 0\%$ - plane $u = 0$, (b) $\delta\alpha_n = 10\%$ - plane $u = 0$

(c) $\delta\alpha_n = 0\%$ - plane $v = 0$, (d) $\delta\alpha_n = 10\%$ - plane $v = 0$

Amplitude Error: $\delta\alpha_n = 0\%$ - Plane $u = 0$

$N \times M / \delta\beta_n$ [deg]	Cartesian			Minkowski		
	1	5	10	1	5	10
48	[-21.15, -18.91]	[-27.79, -15.11]	[-∞, -11.53]	[-21.14, -18.97]	[-26.80, -15.60]	[-∞, -12.44]
96	[-21.02, -18.97]	[-27.19, -15.29]	[-∞, -11.80]	[-21.01, -19.00]	[-26.94, -15.71]	[-∞, -12.54]
128	[-21.02, -18.97]	[-27.19, -15.29]	[-∞, -11.80]	[-21.01, -19.00]	[-26.94, -15.71]	[-∞, -12.54]
200	[-20.95, -18.95]	[-26.25, -15.18]	[-∞, -11.59]	[-20.94, -19.01]	[-25.97, -15.77]	[-∞, -12.60]

Table: Interval *SLL* vs $N \times M$ - $\delta\alpha_n = 0\%$ - Cartesian vs Minkowski sum

Amplitude Error: $\delta\alpha_n = 0\%$ - Plane $v = 0$

$N \times M / \delta\beta_n$ [deg]	Cartesian			Minkowski		
	1	5	10	1	5	10
48	[-21.02, -18.97]	[-27.19, -15.29]	$[-\infty, -11.80]$	[-21.01, -19.00]	[-26.93, -15.71]	$[-\infty, -12.54]$
96	[-20.98, -18.99]	[-26.73, -15.35]	$[-\infty, -11.86]$	[-20.97, -19.00]	[-26.47, -15.78]	$[-\infty, -12.61]$
128	[-20.90, -19.00]	[-25.84, -15.37]	$[-\infty, -11.88]$	[-20.89, -19.04]	[-25.59, -15.80]	$[-44.48, -12.63]$
200	[-20.95, -19.01]	[-26.55, -15.38]	$[-\infty, -11.88]$	[-20.95, -19.06]	[-26.27, -15.83]	$[-\infty, -12.66]$

Table: Interval SLL vs $N \times M$ - $\delta\alpha_n = 0\%$ - Cartesian vs Minkowski sum

Amplitude Error: $\delta\alpha_n = 10\%$ - Plane $u = 0$

$N \times M / \delta\beta_n$ [deg]	Cartesian			Minkowski		
	1	5	10	1	5	10
48	[-31.12, -12.98]	$[-\infty, -10.22]$	$[-\infty, -7.50]$	[-30.59, -13.89]	$[-\infty, -11.76]$	$[-\infty, -9.64]$
96	[-31.49, -13.41]	$[-\infty, -10.78]$	$[-\infty, -8.06]$	[-31.16, -14.16]	$[-\infty, -12.08]$	$[-\infty, -9.99]$
128	[-31.49, -13.41]	$[-\infty, -10.78]$	$[-\infty, -8.06]$	[-31.16, -14.16]	$[-\infty, -12.08]$	$[-\infty, -10.0]$
200	[-31.62, -12.96]	$[-\infty, -10.23]$	$[-\infty, -7.51]$	[-31.16, -13.80]	$[-\infty, -11.76]$	$[-\infty, -9.70]$

Table: Interval SLL vs $N \times M$ - $\delta\alpha_n = 10\%$ - Cartesian vs Minkowski sum

Amplitude Error: $\delta\alpha_n = 10\%$ - Plane $v = 0$

$N \times M / \delta\beta_n$ [deg]	Cartesian			Minkowski		
	1	5	10	1	5	10
48	[-31.49, -13.41]	$[-\infty, -10.78]$	$[-\infty, -8.06]$	[-31.15, -14.16]	$[-\infty, -12.08]$	$[-\infty, -10.00]$
96	[-31.70, -13.32]	$[-\infty, -10.65]$	$[-\infty, -7.99]$	[-31.34, -14.07]	$[-\infty, -12.10]$	$[-\infty, -10.00]$
128	[-31.78, -13.32]	$[-\infty, -10.72]$	$[-\infty, -8.09]$	[-31.40, -14.05]	$[-\infty, -12.13]$	$[-\infty, -10.01]$
200	[-31.81, -13.34]	$[-\infty, -10.75]$	$[-\infty, -8.03]$	[-31.42, -14.07]	$[-\infty, -12.17]$	$[-\infty, -10.02]$

Table: Interval SLL vs $N \times M$ - $\delta\alpha_n = 0\%$ - Cartesian vs Minkowski

1.1.3 Pattern Features - Interval Power Peak - $(u, v) = (0, 0)$

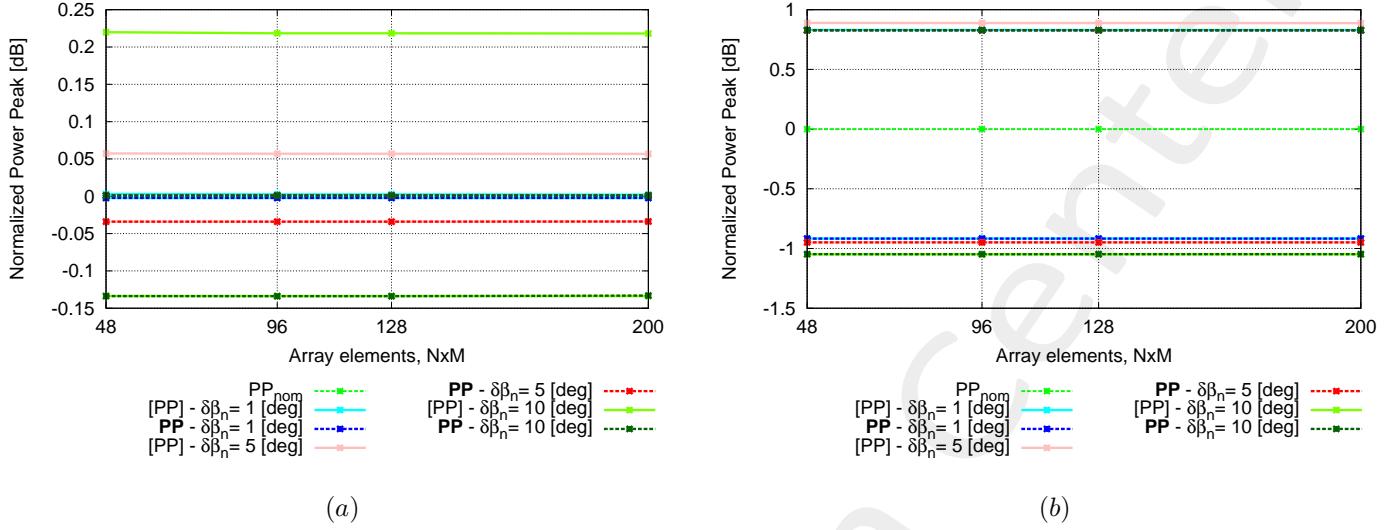


Table: Interval PP comparison Cartesian vs Minkowski sum

(a) $\delta\alpha_n = 0\%$, (b) $\delta\alpha_n = 10\%$

Amplitude Error: $\delta\alpha_n = 0\%$

		Cartesian			Minkowski		
$N \times M / \delta\beta_n$ [deg]	1	5	10	1	5	10	
48	$[-2.19, 3.08] \times 10^{-3}$	$[-3.39, 5.75] \times 10^{-2}$	$[-1.33, 2.20] \times 10^{-1}$	$[-2.19, 0.0] \times 10^{-3}$	$[-3.39, 0.0] \times 10^{-2}$	$[-1.33, 0.0] \times 10^{-1}$	
96	$[-2.19, 2.60] \times 10^{-3}$	$[-3.39, 5.70] \times 10^{-2}$	$[-1.33, 2.18] \times 10^{-1}$	$[-2.19, 0.0] \times 10^{-3}$	$[-3.39, 0.0] \times 10^{-2}$	$[-1.33, 0.0] \times 10^{-1}$	
128	$[-2.19, 2.60] \times 10^{-3}$	$[-3.39, 5.70] \times 10^{-2}$	$[-1.33, 2.18] \times 10^{-1}$	$[-2.19, 0.0] \times 10^{-3}$	$[-3.39, 0.0] \times 10^{-2}$	$[-1.33, 0.0] \times 10^{-1}$	
200	$[-2.19, 2.19] \times 10^{-3}$	$[-3.39, 5.70] \times 10^{-2}$	$[-1.33, 2.20] \times 10^{-1}$	$[-2.19, 0.0] \times 10^{-3}$	$[-3.39, 0.0] \times 10^{-2}$	$[-1.33, 0.0] \times 10^{-1}$	

Table: Interval PP vs $N \times M$ - $\delta\alpha_n = 0\%$ - Cartesian vs Minkowski sum

Amplitude Error: $\delta\alpha_n = 10\%$

		Cartesian			Minkowski		
$N \times M / \delta\beta_n$ [deg]	1	5	10	1	5	10	
48	$[-0.91, 0.83]$	$[-0.95, 0.89]$	$[-1.05, 1.06]$	$[-0.91, 0.83]$	$[-0.95, 0.83]$	$[-1.05, 0.83]$	
96	$[-0.91, 0.83]$	$[-0.95, 0.89]$	$[-1.05, 1.06]$	$[-0.91, 0.83]$	$[-0.95, 0.83]$	$[-1.05, 0.83]$	
128	$[-0.91, 0.83]$	$[-0.95, 0.89]$	$[-1.05, 1.06]$	$[-0.91, 0.83]$	$[-0.95, 0.83]$	$[-1.05, 0.83]$	
200	$[-0.91, 0.83]$	$[-0.95, 0.89]$	$[-1.05, 1.06]$	$[-0.91, 0.83]$	$[-0.95, 0.83]$	$[-1.05, 0.83]$	

Table: Interval PP vs $N \times M$ - $\delta\alpha_n = 10\%$ - Cartesian vs Minkowski sum

1.1.4 Pattern Features - Pattern Tolerance Δ

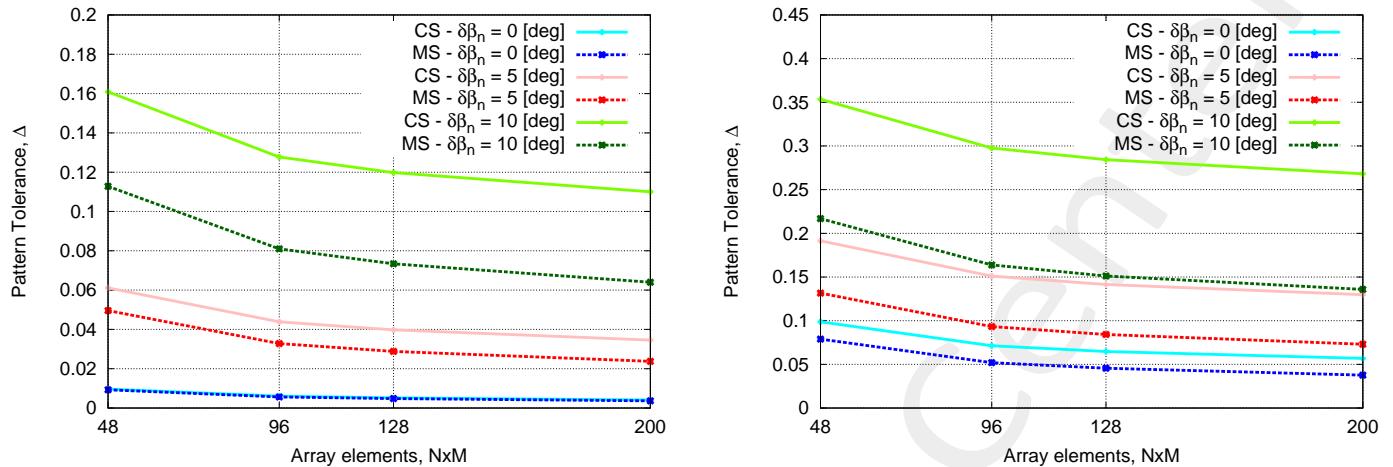


Table: Pattern Matching comparison Cartesian vs Minkowski sum

(a) $\delta\alpha_n = 0\%$, (b) $\delta\alpha_n = 10\%$

Amplitude Error: $\delta\alpha_n = 0\%$

	Cartesian			Minkowski		
	1	5	10	1	5	10
$N \times M / \delta\beta_n$ [deg]						
48	9.66×10^{-3}	6.11×10^{-2}	1.61×10^{-1}	9.28×10^{-3}	4.96×10^{-2}	1.12×10^{-1}
96	6.05×10^{-3}	4.39×10^{-2}	1.27×10^{-1}	5.65×10^{-3}	3.28×10^{-2}	0.81×10^{-1}
128	5.19×10^{-3}	3.97×10^{-2}	1.19×10^{-1}	4.78×10^{-3}	2.88×10^{-2}	0.73×10^{-1}
200	4.07×10^{-3}	3.46×10^{-2}	1.10×10^{-1}	3.68×10^{-3}	2.37×10^{-2}	0.64×10^{-1}

Table: Pattern Tolerance Δ vs $N \times M$ - $\delta\alpha_n = 0\%$ - Cartesian vs Minkowski sum

Amplitude Error: $\delta\alpha_n = 10\%$

	Cartesian			Minkowski		
	1	5	10	1	5	10
$N \times M / \delta\beta_n$ [deg]						
48	9.87×10^{-2}	1.91×10^{-1}	3.53×10^{-1}	7.89×10^{-2}	1.31×10^{-1}	2.16×10^{-1}
96	7.12×10^{-2}	1.51×10^{-1}	2.97×10^{-1}	5.19×10^{-2}	0.93×10^{-1}	1.63×10^{-1}
128	6.47×10^{-2}	1.41×10^{-1}	2.84×10^{-1}	4.55×10^{-2}	0.84×10^{-1}	1.51×10^{-1}
200	5.68×10^{-2}	1.29×10^{-1}	2.68×10^{-1}	3.77×10^{-2}	0.73×10^{-1}	1.36×10^{-1}

Table: Pattern Tolerance Δ vs $N \times M$ - $\delta\alpha_n = 10\%$ - Cartesian vs Minkowski sum

1.1.5 Pattern Features - Normalized Pattern Tolerance Δ_{norm}

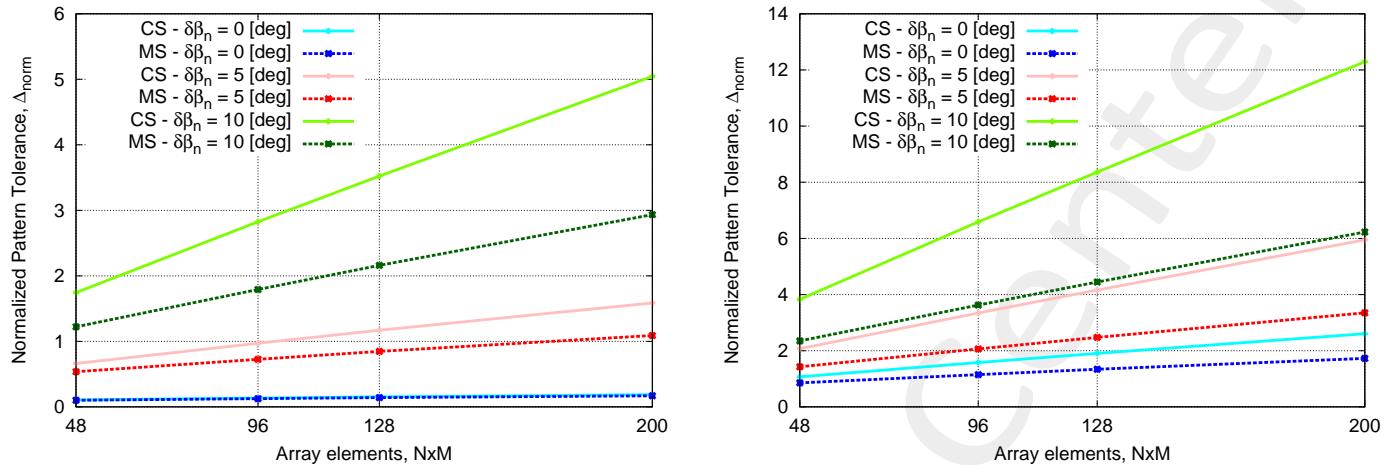


Table: Normalized Pattern Tolerance Δ_{norm} comparison

Cartesian vs Minkowski sum (a) $\delta\alpha_n = 0\%$, (b) $\delta\alpha_n = 10\%$

Amplitude Error: $\delta\alpha_n = 0\%$

	Cartesian			Minkowski		
	1	5	10	1	5	10
48	0.105	0.662	1.743	0.100	0.537	1.222
96	0.134	0.970	2.827	0.125	0.725	1.792
128	0.152	1.170	3.523	0.141	0.846	2.159
200	0.187	1.586	5.045	0.169	1.089	2.934

Table: Δ_{norm} vs $N \times M$ - $\delta\alpha_n = 0\%$ - Cartesian vs Minkowski sum

Amplitude Error: $\delta\alpha_n = 10\%$

	Cartesian			Minkowski		
	1	5	10	1	5	10
48	1.070	2.074	3.830	0.855	1.425	2.349
96	1.577	3.343	6.588	1.149	2.065	3.627
128	1.905	4.160	8.363	1.339	2.475	4.447
200	2.604	5.949	12.29	1.728	3.348	6.228

Table: Δ_{norm} vs $N \times M$ - $\delta\alpha_n = 10\%$ - Cartesian vs Minkowski sum

1.1.6 Comments and Observations:

When increasing the number of radiating elements, the normalize pattern tolerance Δ_{norm} increases. This means that in large arrays the deviation from the nominal pattern is grater than in small arrays. However, this not affect to much the pattern features (more specifically the *SLL* and *PP* losses), that seem to be almost constant with respect to number of radiating elements.

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